


<b>Search Notes</b>  	<b>Application/Control No.</b>  10042323	<b>Applicant(s)/Patent Under Reexamination</b>  OKAZAWA, TAKASHI
	<b>Examiner</b>  Rodriguez, Lennin R	<b>Art Unit</b>  2625

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
text search (see attached search history)	6/13/2010	LR
358/1.11-1.18 with keyword search	6/13/2010	LR
PAJ- Japanese database	6/13/2010	LR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/L. R. R./ Examiner.Art Unit 2625	
--------------------------------------	--